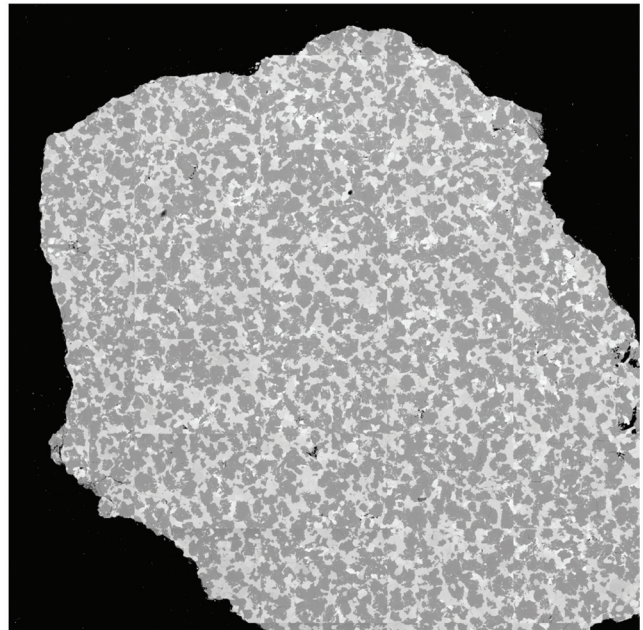
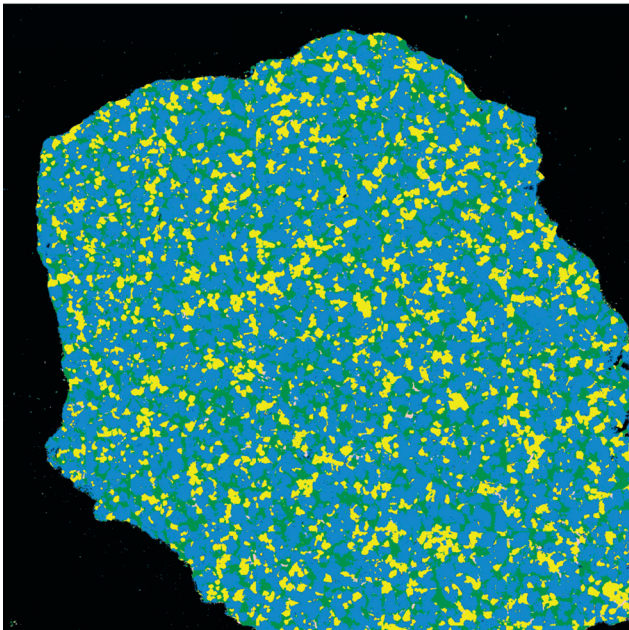
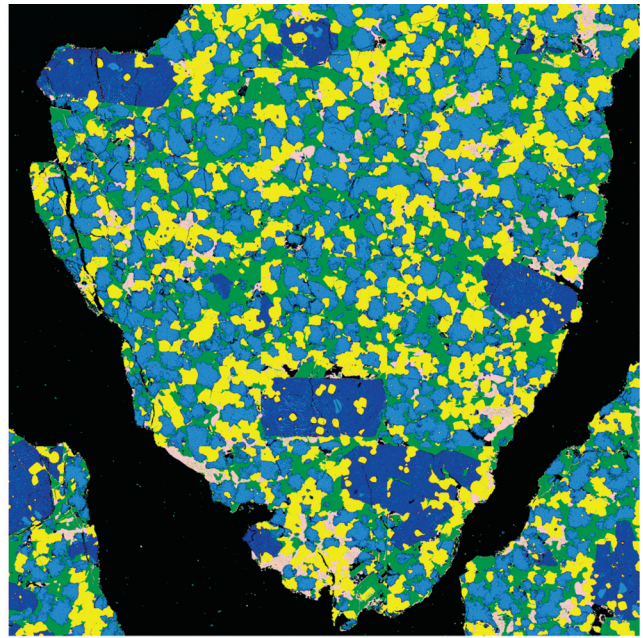
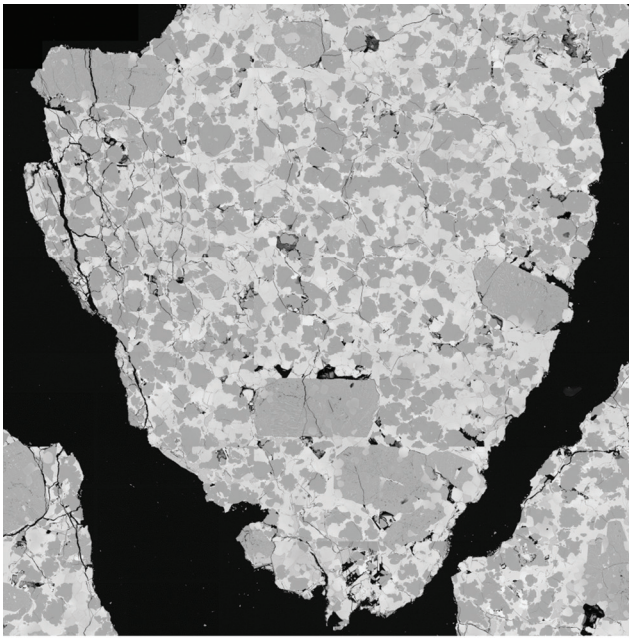


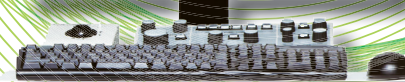
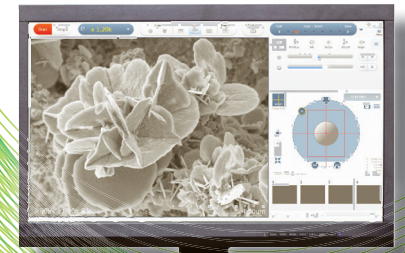
# Microscopy TODAY

Volume 24 Number 5 2016 September



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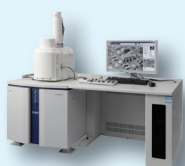
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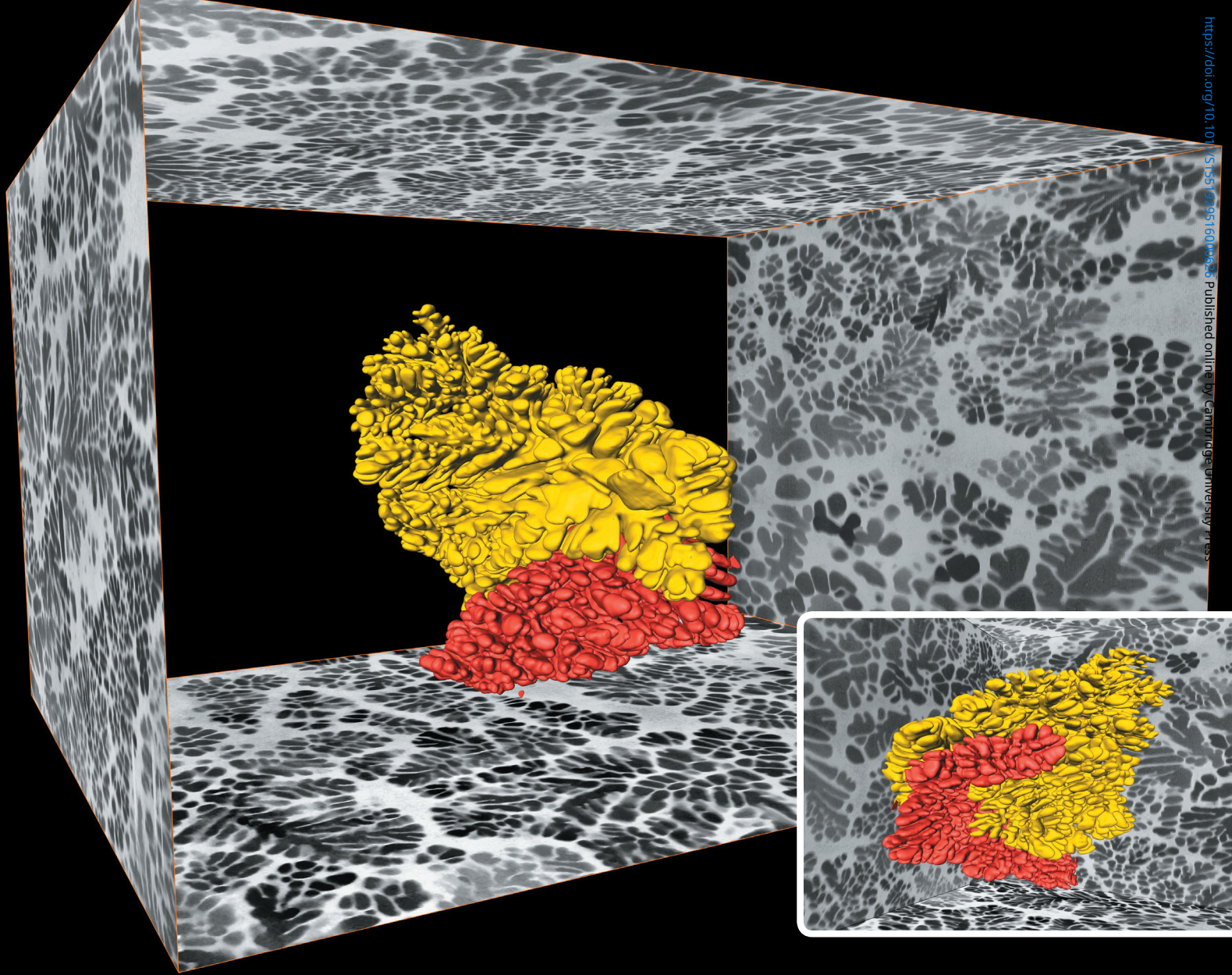
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FEI Avizo® 3D visualization of two large adjacent crystalline dendrites of a bulk-metallic-glass matrix composite ( $Zr_{58.5}Ti_{14.3}Nb_{5.2}Cu_{6.1}Ni_{4.9}Be_{10}$ ). Data was obtained by large volume serial sectioning tomography using the Helios PFIB DualBeam. The sectioned block is about  $90 \times 80 \times 70 \mu m^3$ . Sample from The University of Tennessee, USA. Images courtesy of The University of Manchester.

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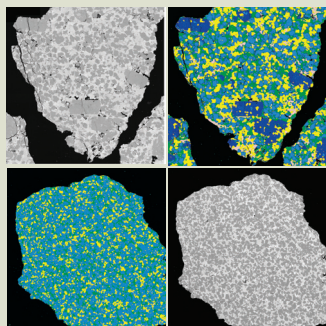
Alwyn Eades

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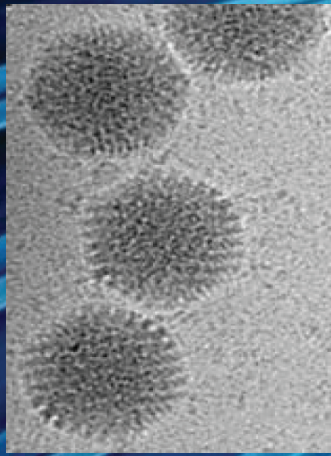
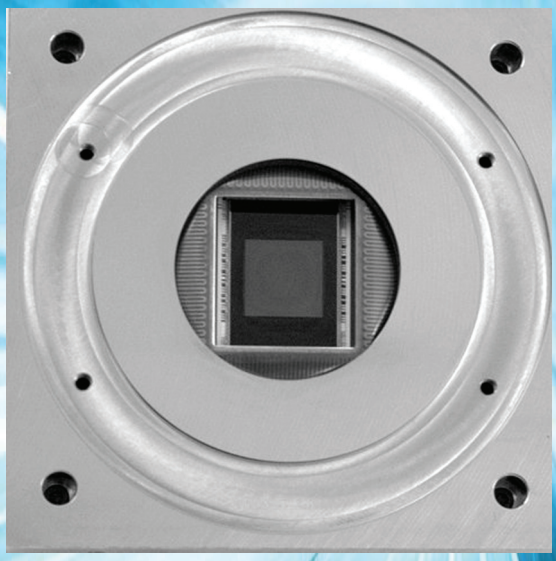
Large-area sections of metallurgical slag grains from steelmaking. Clockwise from upper left: backscattered electron image of lime-bearing grain, phase image of same grain, BSE image of lime-free grain, and phase image of this grain. Image width = 2.56 mm

See article by van Hoek et al.



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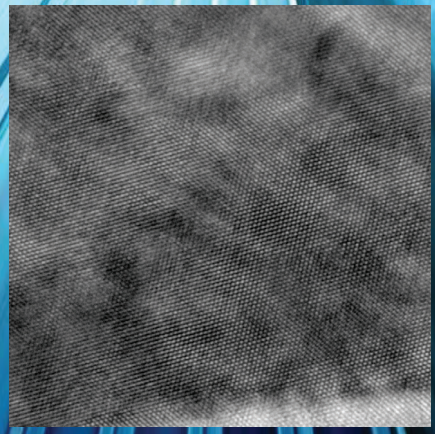
Adenovirus

Dr. Cameron Ackerley  
The Hospital for Sick Children



Diffraction

Dr. Pengfei Hu at the Shanghai University



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